

IIT/CIF/2026-27/04/02

30.04.2026

Minutes of the Pre-bid meeting held for the Notice inviting tender for the supply, installation, testing, commissioning and training of Atomic Force Microscope published on the CPP Portal.

The tender for the supply, installation, testing, commissioning and training of the Atomic Force Microscope was published on the CPP portal on 07.04.2026. The pre-bid meeting for the same was conducted in hybrid mode on 15.04.2026, 11.30 AM in the Dean (Admin & Finance) meeting room.

The following members were present to provide clarification on tender specifications:

- 1) Mr M. Ravi Sankar, Professor, Central Instrumentation Facility - Convenor
- 2) Mr Sourav Chakraborty, Associate Professor, Central Instrumentation Facility
- 3) Mr Umesh Kumar Singh, Assistant Registrar, Purchase & Stores
- 4) Mr Avinash Patsha, Assistant Professor, Physics Department
- 5) Mr Achintya Jana, Technical Officer, Central Instrumentation Facility

The following prospective bidders attended the pre-bid meeting in online & offline modes.

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| 1) Toshniwal bros(SR) Pvt Ltd | - Offline mode |
| 2) Park Systems India | - Offline mode |
| 3) Labindia Instruments Pvt Ltd | - Offline mode |
| 4) Bruker India | - Online mode |
| 5) Laser Science Services Pvt Ltd | - Online mode |
| 6) Inkarp Instruments Pvt Ltd | - Online mode |

Summary of the meeting:

- 1) At the outset, the bidders were welcomed by the committee members.
- 2) The convenor then briefed about the procurement and institute requirements.
- 3) Thereafter, the participants were invited to raise their queries, a few of which were addressed in the pre-bid meeting and the same is recorded.

The queries of the bidders are as follows:-

A. Query Raised By: Toshniwal Brothers (SR) Private Limited

Technical Specifications: Schedule of Requirements SI No	Query Description		
	Tender Parameters	Tender Specs.	Changes/Clarification requested
2 (Page No 02 of 48)	Application modes	System should be supplied with a total of 8 inbuilt lock-in amplifiers or total of 8 built-in and external amplifiers to support various functions of AFM.	We kindly request a revision of the Highlighted specification. In our understanding the current requirement is available form only one AFM manufacturer. <i>“System should be supplied with a total of 4 or more inbuilt lock-in amplifiers or total of 4 or more built-in and external amplifiers to support various functions of AFM.”</i> Please note that this is a system design aspect which based on individual design philosophy applications/modes of operation are met and rendered capable.
2(Page No 02 of 48)	Application modes	Magnetic Force Microscopy (MFM) Capable of both amplitude-modulation (AM) & frequency-modulation (FM).	We kindly request a revision of the highlighted specification: <i>“Magnetic Force Microscopy (MFM) Capable with amplitude-modulation (AM) or more.”</i>
3(Page No 03 of 48)	Auto Laser Source/Detector/Probe exchange	Automatic probe exchange or equivalent technology for ease of operation is preferred and can be quoted as standard or optional item.	We kindly request a revision of the highlighted specification. <i>“Automatic probe exchange or equivalent technology like pre-mounted probes for ease of operation is preferred and can be quoted as optional item.”</i>
7(Page No 04 of 48).	Scanners: The instrument design should allow the use of two or more scanners to cover a large area and high resolution imaging.	System must include a Z scanner with a range of at least 15 µm, and capable of both open-loop and closed-loop operation. Noise on the Z sensor must be 0.05 nm or less @1 kHz RMS bandwidth or less, with dual servo closed feedback for getting accurate imaging.	We kindly request a revision of the highlighted specification. <i>“System must include a Z scanner with a range of at least 10 µm or more, and capable of both open-loop and closed-loop operation. Noise on the Z sensor must be 0.05 nm or less @1 kHz bandwidth or less, with dual servo closed feedback for getting accurate imaging.”</i>
8(Page No 05 of 48).	Tip-sample viewing / System Optics	Suitable Macro Optics to view 200 mm Stage to be provided for ease of navigation.	We kindly request the deletion of the specification as it is not available with most vendors.

B. Query Raised By: Park Systems India Private Limited

Technical Specifications: Schedule of Requirements SI No	Query Description		
	Tender Parameters	Tender Specs.	Changes/Clarification requested
14(Page No 06 of 48).	Sample Stretching Stage for AFM	The Accessory should be quoted with a high-strain, high-travel manual stretching stage....	<p>Following are to be included in Stretching stage (Tensile micro stage) for nano mechanical AFM analysis</p> <ul style="list-style-type: none"> • Tensile • Compression • Bending • Fatigue <p>Sample size range from 10 mm to 40 mm or more</p> <p>With maximum strain travel up to 25 mm or more</p> <p>With a linear accuracy of 20 nm or less.</p>

C. Query Raised By: (i) Inkarp Instruments Pvt. Ltd.; (ii) Labindia Instruments Pvt.Ltd.

Technical Specifications: Schedule of Requirements SI No	Query Description		
	Tender Parameters	Tender Specs.	Changes/Clarification requested
7(Page No 04 of 48).	Scanners: The instrument design should allow the use of two or more scanners to cover a large area and high resolution imaging.	System must be capable of high speed closed-loop imaging up to 20 Hz or more	Clarification requested. The sentence may be modified.

It was informed to the bidders that the relevant corrigendum to the tender document will be uploaded on the CPP portal & Institute website after due discussion with the technical evaluation committee members regarding the technical specifications.